

CBTU04083

**1.8 V, wide bandwidth, 4 differential channel,
2 : 1 multiplexer/demultiplexer switch**

Rev. 1 — 16 July 2010

Product data sheet

1. General description

CBTU04083 is an 8-to-4 differential channel multiplexer/demultiplexer switch. The CBTU04083 can switch four differential signals to one of two locations. Using a unique design technique, NXP has minimized the impedance of the switch such that the attenuation observed through the switch is negligible, and also minimized the channel-to-channel skew as well as channel-to-channel crosstalk, as required by the high-speed serial interface. CBTU04083 allows expansion of existing high speed ports for extremely low power.

2. Features and benefits

- 4 differential channel, 2 : 1 multiplexer/demultiplexer
- High-speed signal switching; 8.0 Gbit/s
- Low intra-pair skew: 10 ps maximum (between positive and negative bits)
- Low inter-pair skew: 35 ps maximum
- Low crosstalk: -30 dB at 4 GHz
- Low off-state isolation: -30 dB at 4 GHz
- V_{DD} operating range: 1.8 V ± 10 %
- ESD tolerance:
 - ◆ 6 kV HBM
 - ◆ 1 kV CDM
- HVQFN42 package

3. Applications

- Routing of high-speed differential signals with low signal attenuation
 - ◆ PCIe Gen3
 - ◆ DisplayPort 1.2
 - ◆ USB 3.0
 - ◆ SATA 6 Gbit/s



4. Ordering information

Table 1. Ordering information

| Type number | Package | | Version |
|-------------|---------|---|-----------|
| | Name | Description | |
| CBTU04083BS | HVQFN42 | plastic thermal enhanced very thin quad flat package; no leads; 42 terminals; body 3.5 × 9 × 0.85 mm | SOT1144-1 |

5. Functional diagram

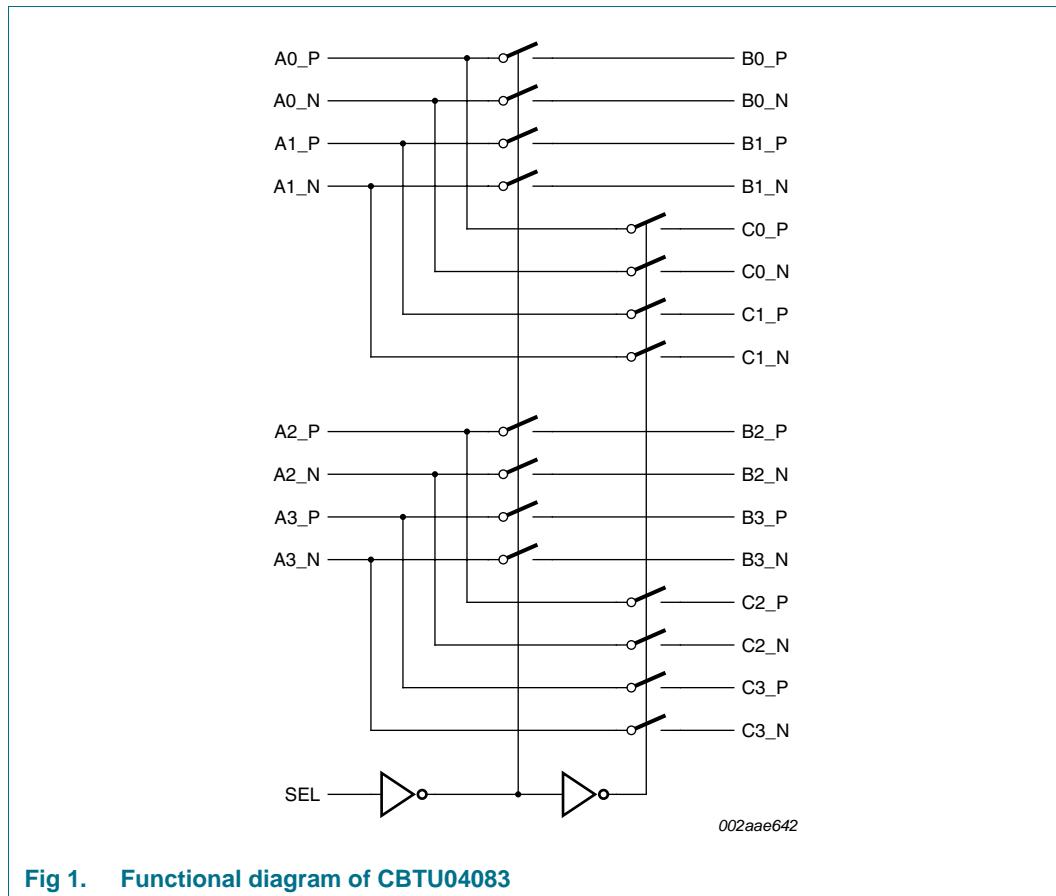


Fig 1. Functional diagram of CBTU04083

6. Pinning information

6.1 Pinning

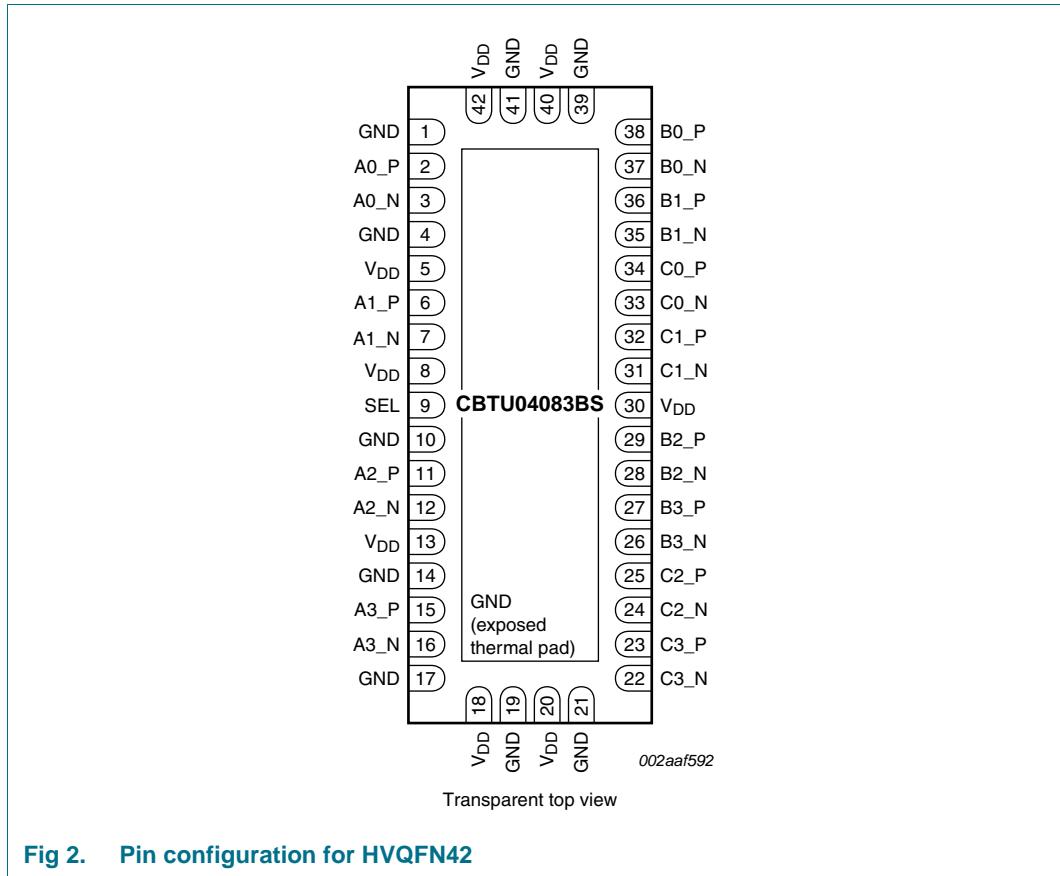


Fig 2. Pin configuration for HVQFN42

6.2 Pin description

Table 2. Pin description

| Symbol | Pin | Type | Description |
|--------|-----|------|--|
| A0_P | 2 | I/O | channel 0, port A differential signal input/output |
| A0_N | 3 | I/O | |
| A1_P | 6 | I/O | channel 1, port A differential signal input/output |
| A1_N | 7 | I/O | |
| A2_P | 11 | I/O | channel 2, port A differential signal input/output |
| A2_N | 12 | I/O | |
| A3_P | 15 | I/O | channel 3, port A differential signal input/output |
| A3_N | 16 | I/O | |
| B0_P | 38 | I/O | channel 0, port B differential signal input/output |
| B0_N | 37 | I/O | |
| B1_P | 36 | I/O | channel 1, port B differential signal input/output |
| B1_N | 35 | I/O | |

Table 2. Pin description ...*continued*

| Symbol | Pin | Type | Description |
|-----------------|--|----------------------------|--|
| B2_P | 29 | I/O | channel 2, port B differential signal input/output |
| B2_N | 28 | I/O | |
| B3_P | 27 | I/O | channel 3, port B differential signal input/output |
| B3_N | 26 | I/O | |
| C0_P | 34 | I/O | channel 0, port C differential signal input/output |
| C0_N | 33 | I/O | |
| C1_P | 32 | I/O | channel 1, port C differential signal input/output |
| C1_N | 31 | I/O | |
| C2_P | 25 | I/O | channel 2, port C differential signal input/output |
| C2_N | 24 | I/O | |
| C3_P | 23 | I/O | channel 3, port C differential signal input/output |
| C3_N | 22 | I/O | |
| SEL | 9 | CMOS single-ended input | operation mode select SEL = LOW: A → B SEL = HIGH: A → C |
| V _{DD} | 5, 8, 13, 18, 20, 30, 40, 42 | power | positive supply voltage, 1.8 V to 2.0 V (± 0.1 V) |
| GND | 1, 4, 10, 14, 17, 19, 21, 39, 41, center pad | power | supply ground |

7. Functional description

Refer to [Figure 1 “Functional diagram of CBTU04083”](#).

7.1 Function selection

Table 3. Function selection

| SEL | Function |
|------------|-----------------|
| LOW | An to Bn |
| HIGH | An to Cn |

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-------------------|---------------------------------|------------|------|------|--------|
| V _{DD} | supply voltage | | -0.5 | +2.5 | V |
| T _{case} | case temperature | | -40 | +85 | °C |
| V _{ESD} | electrostatic discharge voltage | HBM | [1] | - | 6000 V |
| | | CDM | [2] | - | 1000 V |

[1] Human Body Model: ANSI/ESD/ESD-S5.1-1994, standard for ESD sensitivity testing, Human Body Model - Component level; Electrostatic Discharge Association, Rome, NY, USA.

[2] Charged Device Model: ANSI/ESD/ESD-S5.3-1-1999, standard for ESD sensitivity testing, Charged Device Model - Component level; Electrostatic Discharge Association, Rome, NY, USA.

9. Recommended operating conditions

Table 5. Recommended operating conditions

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|------------------|---------------------|-----------------------|------|-----|-----------------|------|
| V _{DD} | supply voltage | | 1.62 | 1.8 | 1.98 | V |
| V _I | input voltage | | -0.5 | - | V _{DD} | V |
| T _{amb} | ambient temperature | operating in free air | -40 | - | +85 | °C |

10. Static characteristics

Table 6. Static characteristicsV_{DD} = 1.8 V ± 10 %; T_{amb} = -40 °C to +85 °C; unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-----------------|--------------------------|---|---------------------|------|---------------------|------|
| I _{DD} | supply current | V _{DD} = max.; V _I = GND or V _{DD} | - | - | 4 | mA |
| I _{IH} | HIGH-level input current | V _{DD} = max.; V _I = V _{DD} | - | - | ±5[2] | µA |
| I _{IL} | LOW-level input current | V _{DD} = max.; V _I = GND | - | - | ±5[2] | µA |
| V _{IH} | HIGH-level input voltage | SEL pin | 0.65V _{DD} | - | - | V |
| V _{IL} | LOW-level input voltage | SEL pin | -0.5 | - | 0.15V _{DD} | V |
| V _{IK} | input clamping voltage | V _{DD} = max.; I _I = -18 mA | - | -0.7 | -1.2 | V |

[1] Typical values are at V_{DD} = 1.8 V, T_{amb} = 25 °C, and maximum loading.

[2] Input leakage current is ±50 µA if differential pairs are pulled to HIGH and LOW.

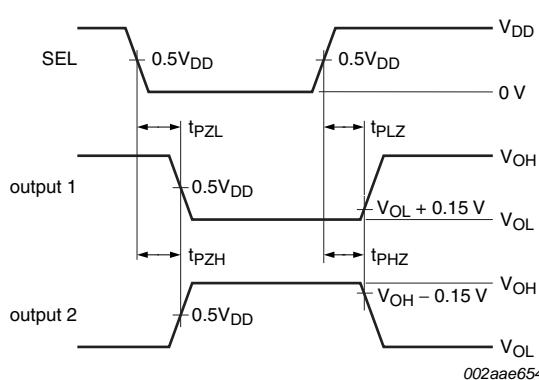
11. Dynamic characteristics

Table 7. Dynamic characteristics

$V_{DD} = 1.8 \text{ V} \pm 10\%$; $T_{amb} = -40^\circ\text{C}$ to $+85^\circ\text{C}$; unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Typ[1] | Max | Unit |
|----------------------------------|-------------------------------------|---|-----|--------|-----|------|
| α_{ct} | crosstalk attenuation | $f = 4 \text{ GHz}$ | - | -30 | - | dB |
| | | $f = 100 \text{ MHz}$ | - | -70 | - | dB |
| $\alpha_{iso(off)}$ | off-state isolation | $f = 4 \text{ GHz}$ | - | -30 | - | dB |
| | | $f = 100 \text{ MHz}$ | - | -60 | - | dB |
| DDIL | differential insertion loss | $f = 4 \text{ GHz}$ | - | -2.8 | - | dB |
| | | $f = 100 \text{ MHz}$ | - | -0.5 | - | dB |
| $B_{-3\text{dB}}$ | -3 dB bandwidth | | - | 4.3 | - | GHz |
| t_{PD} | propagation delay | from left-side port to right-side port, or vice versa | - | 80 | - | ps |
| Switching characteristics | | | | | | |
| t_{PZH} | OFF-state to HIGH propagation delay | | - | - | 8.0 | ns |
| t_{PZL} | OFF-state to LOW propagation delay | | - | - | 8.0 | ns |
| t_{PHZ} | HIGH to OFF-state propagation delay | | - | - | 8.0 | ns |
| t_{PLZ} | LOW to OFF-state propagation delay | | - | - | 8.0 | ns |
| $t_{sk(dif)}$ | differential skew time | intra-pair | - | - | 10 | ps |
| t_{sk} | skew time | inter-pair | - | - | 35 | ps |

[1] Typical values are at $V_{DD} = 1.8 \text{ V}$; $T_{amb} = 25^\circ\text{C}$, and maximum loading.



Output 1 is for an output with internal conditions such that the output is LOW except when disabled by the output control.

Output 2 is for an output with internal conditions such that the output is HIGH except when disabled by the output control.

The outputs are measured one at a time with one transition per measurement.

Fig 3. Voltage waveforms for enable and disable times

12. Test information

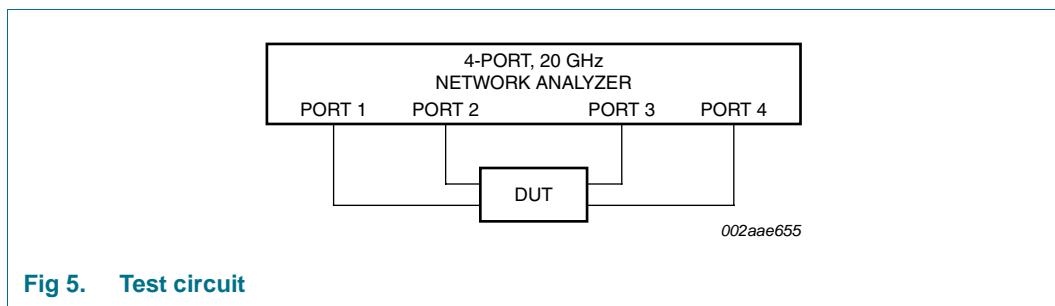
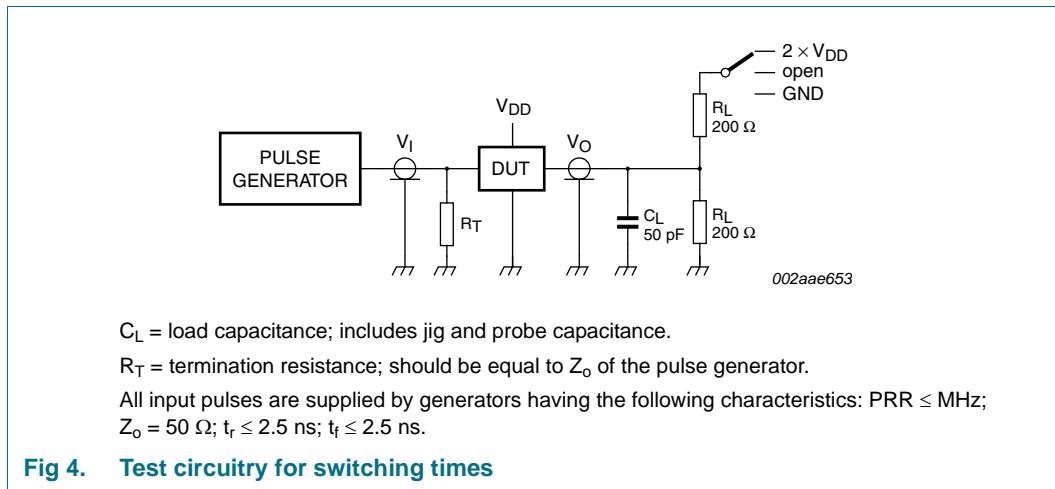


Table 8. Test data

| Test | Load | | Switch |
|---------------------------------------|-------|--------------|-------------------|
| | C_L | R_L | |
| t_{PLZ}, t_{PZL} (output on B side) | 50 pF | 200 Ω | $2 \times V_{DD}$ |
| t_{PHZ}, t_{PZH} (output on B side) | 50 pF | 200 Ω | GND |
| t_{PD} | 50 pF | 200 Ω | open |

13. Package outline

HVQFN42: plastic thermal enhanced very thin quad flat package; no leads;
42 terminals; body 3.5 x 9 x 0.85 mm

SOT1144-1

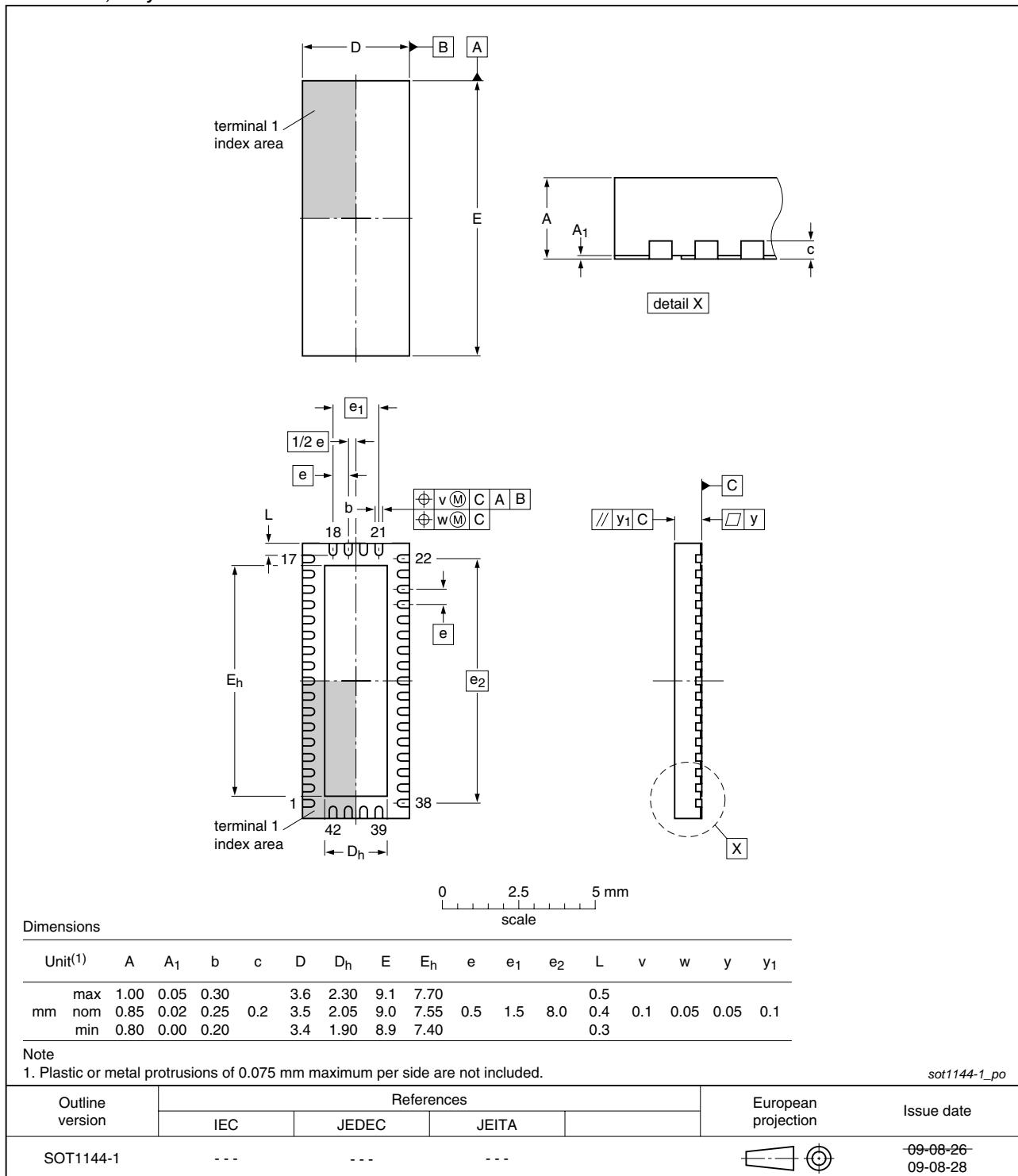


Fig 6. Package outline SOT1144-1 (HVQFN42)

14. Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note AN10365 “Surface mount reflow soldering description”.

14.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

14.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering

14.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- Solder bath specifications, including temperature and impurities

14.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see [Figure 7](#)) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with [Table 9](#) and [10](#)

Table 9. SnPb eutectic process (from J-STD-020C)

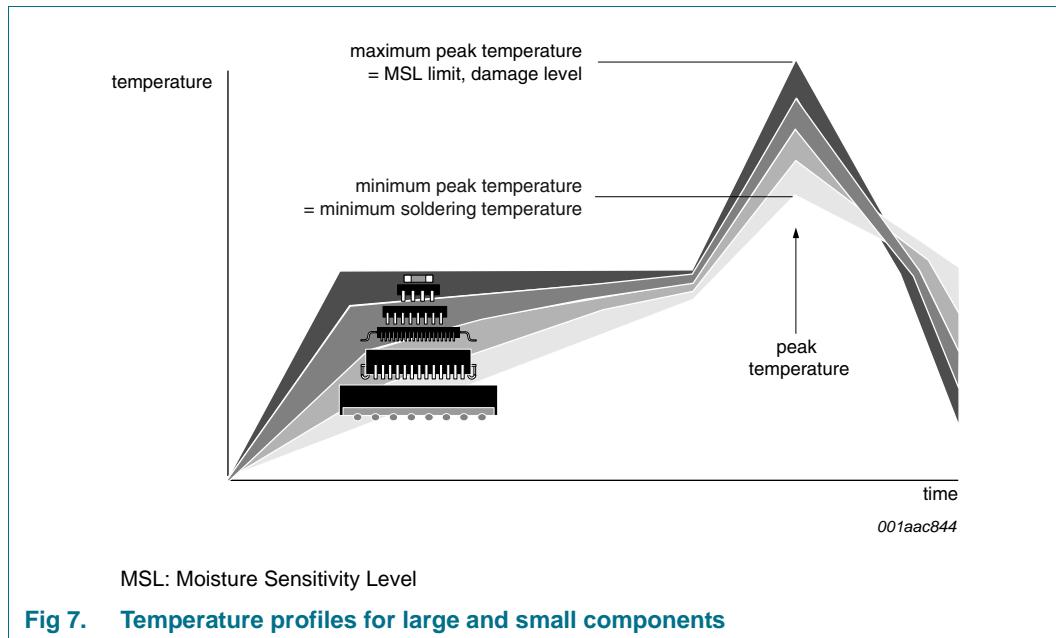
| Package thickness (mm) | Package reflow temperature (°C) | |
|------------------------|---------------------------------|-------|
| | Volume (mm ³) | |
| | < 350 | ≥ 350 |
| < 2.5 | 235 | 220 |
| ≥ 2.5 | 220 | 220 |

Table 10. Lead-free process (from J-STD-020C)

| Package thickness (mm) | Package reflow temperature (°C) | | |
|------------------------|---------------------------------|-------------|--------|
| | Volume (mm ³) | | |
| | < 350 | 350 to 2000 | > 2000 |
| < 1.6 | 260 | 260 | 260 |
| 1.6 to 2.5 | 260 | 250 | 245 |
| > 2.5 | 250 | 245 | 245 |

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see [Figure 7](#).



For further information on temperature profiles, refer to Application Note AN10365 "Surface mount reflow soldering description".

15. Abbreviations

Table 11. Abbreviations

| Acronym | Description |
|---------|---------------------------------------|
| CDM | Charged-Device Model |
| DUT | Device Under Test |
| ESD | ElectroStatic Discharge |
| HBM | Human Body Model |
| I/O | Input/Output |
| LVDS | Low-Voltage Differential Signalling |
| PCI | Peripheral Component Interconnect |
| PCIe | PCI express |
| PRR | Pulse Repetition Rate |
| SATA | Serial Advanced Technology Attachment |
| USB | Universal Serial Bus |

16. Revision history

Table 12. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|---------------|--------------|--------------------|---------------|------------|
| CBTU04083 v.1 | 20100716 | Product data sheet | - | - |

17. Legal information

17.1 Data sheet status

| Document status ^{[1][2]} | Product status ^[3] | Definition |
|-----------------------------------|-------------------------------|---|
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